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(71)Applicant : OLYMPUS OPTICAL CO LTD

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(72)Inventor : TODA AKITOSHI

TADOKORO KAORU

OSADA TAIJI

SHINOHARA ETSUO

ENOMOTO YOSHIMITSU

TAKAYAMA MICHIO

OTA AKIRA

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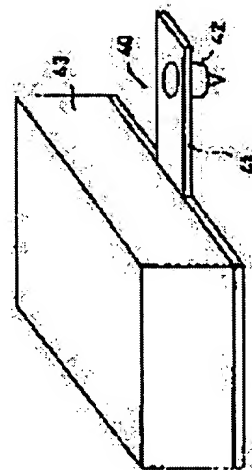
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(54) CANTILEVER FOR SCANNING TYPE PROBE MICROSCOPE AND MANUFACTURE THEREOF

(57)Abstract:

PURPOSE: To provide a cantilever provided with a probe part having a sharp tip and proper length.

CONSTITUTION: A cantilever 40 for a scanning type probe microscope is equipped with a lever part 40 and the probe part 42 arranged on the free end side thereof. The probe part 42 consists of a conical tip part 45 having a sharp tip angle and the expanded base end part 44 continued to the tip part 45. The cantilever 40 is prepared by utilizing a semiconductor process.

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